## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | HAGAI ET AL. | Examiner | Art Unit | Pawandeep S. Dhingra | 2625 | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,387,987 A	02-1995	Ino, Naosuke	358/3.03
*	В	US-5,870,503 A	02-1999	Kumashiro, Hideo	382/252
*	С	US-6,195,468 B1	02-2001	Yoshida, Yasunari	382/270
*	D	US-6,625,327 B1	09-2003	Ohshima et al.	382/270
*	E	US-2003/0169455 A1	09-2003	Takahashi et al.	358/3.03
*	F	US-6,917,446 B2	07-2005	Tanaka et al.	358/1.9
*	G	US-2005/0219621 A1	10-2005	Yamamoto, Toshitsugu	358/003.03
*	н	US-7,009,731 B1	03-2006	Yamamoto, Toshitsugu	358/1.9
*	1	US-7,110,141 B2	09-2006	Yamamoto, Toshitsugu	358/1.9
	J	US-			
	κ	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	Ν	2000-270210	09-2000	JAPAN	Konno Yuji et al.	H04N 1/40
	0					
	Р					
	α					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	כ	
	>	
	>	• .
	×	

<sup>\*</sup>A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.